 Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/830,178	LEE ET AL.
Examiner	Art Unit
Huy C. Ho	2617

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	338	3/22/2007	нн
	254	3/22/2007	нн
455	435.1	3/22/2007	нн
709	249	3/22/2007	нн

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			

	DATE	EXMR
EAST image and keyword search in USPATConclusion, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB (See attached search strategy)	3/22/2007	нн
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